



IEEE 4th International Conference on Computing and Machine
Intelligence
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Central Michigan University

CERTIFICATE

of Participation

This certificate is presented to
Mohammed Nizamul Islam

For participating and presenting the
paper titled:

Classification and Prediction of Wafer Yield Using
Gradient Boosting Algorithms: A focus on
Lithography inline parameters

A handwritten signature in blue ink, appearing to read "Ah".

General Chair
Ahmed Abdelgawad, PhD